Experimental Study of Re-ignition Evaluators in Low Voltage Switching Devices

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Abstract— The re-ignition of the arc during the interruption process deteriorates the switching performance of low voltage switching devices (LVSDs). Avoiding re-ignition is thus a key goal in the effective design of the quenching chamber. A reliable evaluator of re-ignition provides the opportunity to predict the switching performance of a LVSD during the design process and to refine the product prior to manufacture and empirical device testing. In this paper, re-ignition evaluators are investigated through the analysis of interruption test data for several types of LVSDs under the single-phase and three-phase circuit conditions. It is observed that the ratio of the recovery voltage to exit arc voltage, where exit arc voltage is defined as the value of the arc voltage immediately prior to the current zero point, is a reliable evaluator for the prediction of re-ignition in the switching tests of LVSDs. It is also noted that there are no occurrences of instantaneous re-ignition where this voltage ratio lies in the range of 1.0 to -1.0 and there is a threshold of the voltage ratio at approximately -2.0, which can distinguish the successful interruption and instantaneous re-ignition.

Index Terms—Exit arc voltage, low voltage switching device (LVSD), re-ignition evaluator, switching performance, voltage ratio.

I. INTRODUCTION

OW voltage switching devices (LVSDs) are widely utilized in power distribution networks to turn on and off circuits and to protect humans and other connected equipment against overload or short circuit accidents. The quenching chamber of a LVSD is the main volume for switching current and consists of a movable and fixed contact, splitter plate, side plate, magnetic yoke and vent as shown in Fig. 1. When the movable contact separates from the fixed contact, an arc is established in the contact gap which then moves towards the splitter plates by the combination of gas flow and Lorentz forces. After the arc enters the splitter plates, there is an increase in the arc voltage resulting from the multiple anodic and cathodic potential drops associated with the surface interactions with the splitter plates. Ideally, the arc is extinguished at the first current zero moment or sooner in the case of a current limiting device, however the arc can re-ignite after the current zero point.



Fig. 1. Half symmetric geometry of a quenching chamber in an LVSD.

The present market trend for LVSDs is towards a more compact product with higher breaking capacity. In order to produce competitive products meeting this demand with low development costs in a short time, it is essential to predict the switching performance of a LVSD and to optimize a product prior to manufacturing a real device. One of the main factors in the deterioration of the switching performance is re-ignition after the first current zero point. Re-ignition in a LVSD interruption refers to the failure of the arc interruption at the first current zero point; hence the current continues its flow after the current zero point. Re-ignition may lead to longer arcing duration, severe contact erosion and side-wall damage of LVSDs during the interruption process. Avoiding re-ignition is therefore crucial when designing a quenching chamber. In practice a reliable evaluator is required to predict the re-ignition phenomena and to evaluate the switching performance of a particular device prior to empirical testing of real products.

It has been suggested that if the breakdown voltage is greater than the recovery voltage (applied voltage across the breaker at zero current point), there will be a successful interruption without re-ignition [1], [2]; however, the problem of determining the breakdown voltage of the arc plasma after the current zero point has not been fully addressed due to the changes at the breakdown characteristics of the gas-plasma mixture by complex recombination and cooling processes in the breakers. Some experimental studies have been undertaken regarding the breakdown voltage after the current zero point and evaluators of re-ignition in LVSDs in order to achieve the improved performance of switching devices. Shea measured the breakdown voltage depending on the vent area of a quenching chamber and reported that increasing the vent area enhances the breakdown voltage after current interruption [3]. Takahashi and Lindmayer compared the breakdown voltage of the double contacts (U_{Rd}) with that of the single contact (U_{Rs}) and observed that the ratio U_{Rd}/U_{Rs} is 1.7 - 1.8 for Ag alloy contact material, such as AgNi 90/10, AgCdO 90/10 and

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AgSnO₂ 88/12 [4]. Chen et al. investigated the recovery characteristics of the breakdown voltage in four different chambers of the magnetic contactor in an attempt to understand the effect of the configuration of the quenching chamber [5]. More complex evaluators have been also suggested. Balestrero et al. presented the microscopic evaluators that can forecast re-ignition by obtaining the arc voltage or current through a sensitive current measuring device with a signal processing algorithm, for conditions under 10 kA [6], [7]. There were the current decay rate and the change in electric conductivity of the plasma in the microscopic evaluators, however implementation of these evaluators is not an easy task for a large scale evaluation campaign. Hauer et al. introduced the concept of the exit arc voltage, the arc voltage immediately prior to the current zero point, and proposed that the probability of re-ignition after the current zero moment is strongly dependent on the exit arc voltage [8], [9]. It was found that the evaluator of the exit arc voltage is a simple tool, however its reliability has not been rigorously tested. Shin et al. proposed an additional evaluator, the ratio of the system voltage to the exit arc voltage at the current zero point, through the switching test results of the miniature circuit breakers (MCBs) and molded case circuit breakers (MCCBs) [10]. Chen et al. studied the correlation between the arc motion and re-ignition in magnetic contactors by using optic fiber arc imaging technology and found that the better the arc entry into the splitter plates, the less likely the re-ignition [11].

The exit arc voltage could be the simplest evaluator for the industry engineers to evaluate re-ignition phenomena without the complex calculation of the breakdown voltage; however, it has some limitations regarding the test conditions conducted in previous studies and the accuracy of re-ignition evaluation. The previous experimental investigation was carried out under a single circuit condition using a single type of MCCB [8], [9]: hence the reliability of the exit arc voltage needs to be experimentally proved by various kinds of switching conditions. Also, there is no clear threshold value of the exit arc voltage to predict successful interruption. The objective of the work described in this paper is to investigate a more accurate and reliable evaluator for the prediction of re-ignition based on the switching data of various kinds of test conditions. The proposed evaluator, the voltage ratio, is an extension of the exit arc voltage technique. This paper presents the detailed comparison between the exit arc voltage and voltage ratio as a re-ignition evaluator. Further, it shows a clear threshold of the voltage ratio between the successful and failed interruption, which can aid in a LVSD design.

II. EXPERIMENTAL METHODS AND WAVEFORM ANALYSIS

A. Switching Test Circuits and Conditions

The experimental investigation is carried out with 10kA 20kA, 55kA and 100kA test circuits using either MCBs or MCCBs. Figure 2 shows diagrams of the interruption test circuits for single- and three-phase LVSDs. The short-circuit condition is adjusted by a transformer, resistor and reactor. Only R and T phases are utilized for the single-phase tests.



Fig. 2. Test circuit diagrams for a single-phase and three-phase LVSD: (1) back-up circuit breaker, (2) three-phase transformer, (3) making switch, (4) resistor, (5) reactor, (6) single-phase MCB, (7) three-phase MCB or MCCB.

A 13.8 kV commercial power line is used as the power source for the 10 kA and 20 kA switching tests, whereas a short-circuit generator provides the energy for the 55 kA and 100 kA tests. The current and voltage of each phase are recorded by an oscilloscope (10 MHz, Yokogawa DL750), a passive voltage probe (250MHz, Tektronix P5100) and a Rogowski current transducer (16MHz, PEM CWT). No any special filters are used to smooth the waveforms. The observed fluctuations in the waveforms are reflections of a physical phenomenon related to the back and forward motion of the arc at the splitter plates [12].

Table I shows the test condition of each switching case. A total of 110 interruption tests are conducted with previously unused switching devices under five different test circuits. Table II shows the quenching chamber features of the LVSDs used for given switching tests. When the circuit condition is repeated for the tests on the same LVSD type (for example, the switching cases of test number 1 - 26 in Table I), the venting condition varies and some components within the quenching chamber are replaced. This includes changing the geometry of the movable and fixed contact, splitter plate, side plate, magnetic yoke or gassing material. Therefore, there is no identical test condition among 110 switching cases presented in Table I. Testing a variety of circuit conditions and chamber configurations provides the broad switching results for the thorough investigation of re-ignition evaluators.

There are two types of the interruption operation in the switching tests: the open interruption and close-open interruption. The open interruption represents the switching test where short-circuit current starts to flow through a closed LVSD and the contacts automatically open due to short-circuit current. The close-open interruption is the switching test where a LVSD manually operates from the open state to the close state while the system voltage is applied across a device and then the contacts automatically open. The single-phase switching test is conducted through either the open or close-open interruption operation. However, the three-phase test is performed only through the close-open operation in order to obtain an accurate extrapolation of the system voltage at the current zero point. It is difficult to calculate the system voltage at the current zero point by the extrapolation method in a three-phase open interruption test due to distortions observed in the voltage waveforms after switching. The distortions may result from the

TABLE I

TABLE II	
QUENCHING CHAMBER FEATURES OF LVSD	s

Number of phase	Voltage ^a	Prospective current	Power Factor ^b	Kind of LVSDs	Test number °
1	252 V	10 kA	0.45 ^d	63AF °	1 - 26
3	483 V	10 kA	0.45 ^d	MCB	27 - 28
		20 kA	0.3	100AF MCCB	29 - 41
				125AF MCCB	42 - 48
				250AF MCCB	49 - 52
				800AF MCCB	53 - 56
		55 kA	0.2	125AF MCCB	57 - 65
				160AF MCCB	66 -67
				250AF MCCB	68 - 69
				400AF MCCB	70 - 73
				800AF MCCB	74 - 78
		100 kA	0.2	160AF MCCB	79 - 86
				250AF MCCB	87 - 88
				400AF MCCB	89 - 91
				630AF MCCB	92 - 99
				800AF MCCB	100 - 110

^a The voltage value refers to the phase voltage in single-phase tests and line-to-line voltage in three-phase tests.

^b The power factor is selected according to IEC 60947-2 [13].

^c The test number corresponds to the switching data in Fig. 6 and 7.

 $^{\rm d}$ According to IEC 60947-2, the power factor is 0.5 when short-circuit current is 10 kA.

^e Ampere Frame(AF) represents the frame size rating of the LVSD.

step voltage applied to the circuit and associated travelling wave reflection at non-matching impedance points.

B. Waveform Analysis

1) Switching results

There are three possible switching outcomes: 1) a successful interruption without re-ignition, 2) a failed interruption with instantaneous re-ignition or 3) a failed interruption with delayed re-ignition. All interruptions with re-ignition are regarded as failures in this paper. Figure 3 shows the current and voltage waveforms of a successful interruption and two kinds of re-ignition in the switching test of LVSDs. In the successful interruption, the arc is extinguished at the first current zero point without re-ignition (see Fig. 3 (a)). In the case of instantaneous re-ignition, the arc re-ignites and the current continues to flow immediately following the current zero point (see Fig. 3 (b)); however, delayed re-ignition has a pause without current flowing prior to arc re-ignition [8], [9] (see Fig. 3 (c)). It is believed that instantaneous re-ignition is related to a high temperature of the arc plasma, which keeps sufficient electrical conductivity of the residual plasma; whereas, delayed re-ignition relies on the dielectric breakdown which is mainly influenced by the recovery and breakdown

Kind of LVSDs ^a	Type of chamber ^b	Quantity of splitter plates	Parameters ^c
63AF MCB	Single	13	 Venting condition Geometry of movable and fixed contact Geometry of splitter plate Geometry of side plate Geometry and kind of gassing material ^d
100AF MCCB	Single	10	 Venting condition Geometry of splitter plate Geometry of gassing material
125AF MCCB	Single	10	 Venting condition Geometry of splitter plate Geometry of gassing material
160AF MCCB	Double	16	 Venting condition Geometry of magnetic yoke Geometry of gassing material
250AF MCCB	Double	16	 Venting condition Geometry of magnetic yoke ^e Geometry of side plate ^e
400AF MCCB	Double	18	 Geometry of splitter plate Geometry of magnetic yoke
630AF MCCB	Double	18	 Geometry of movable contact Geometry of splitter plate Geometry of magnetic yoke
800AF MCCB	Double	18	 Geometry of movable contact Geometry of splitter plate Geometry of magnetic yoke

^a Each kind of LVSDs has a different configuration of the quenching chamber. In general, the quantity of splitter plates is larger and the volume of a quenching chamber is bigger as the ampere frame (AF) becomes higher.

^b There are two types of quenching chambers in LVSDs: one is a single contact chamber and the other is a double contact chamber.

^cWhen the circuit condition is fixed for the tests on the same kind of the LVSD (for example, the switching cases of test number 1 - 26 in Table I), several design parameters (the venting condition and the geometry of a movable contact, fixed contact, splitter plate, side plate, magnetic yoke or gassing material) of the quenching chamber are changed.

^d The polymer can be placed inside the quenching chamber to improve the switching performance. This polymer is called the gassing material.

^e The side plate and magnetic yoke (shown in Fig. 1) influence the magnetic field in the chamber and they help to increase Lorentz force on the arc.

voltage. Often delayed re-ignition is a consequence of the movable contact's back-motion in the quenching chamber of the LVSD.

2) Exit arc voltage, re-ignition arc voltage and system voltage at the current zero point

To investigate re-ignition evaluators the following parameters are derived from the switching waveforms: the *exit arc voltage*, *re-ignition arc voltage* and *system voltage at the current zero point*. The exit arc voltage is now defined as the value of the arc voltage 20 μ s prior to the current zero point in either successful or failed interruptions, coinciding with the definition provided by Hauer *et al.* [8], [9]. The re-ignition arc voltage is the value of the arc voltage 20 μ s after the current zero point only when instantaneous re-ignition occurs. The system voltage at the current zero point is the value of the supplied voltage across a LVSD when the arc is extinguished or re-ignites.

Figure 4 shows typical current and voltage waveforms during a three-phase interruption process of a MCCB where instantaneous re-ignition occurs in the R phase and the arc is



(a) Waveforms of successful interruption: the fluctuations of the arc voltage between 2 ms and 3 ms are related to the back and forward arc motion at the splitter plates [12].



Fig. 3. Current and voltage waveforms of a successful interruption and two kinds of re-ignition: these are the switching results of single-phase MCBs under 252 V and 10 kA condition.

first extinguished in the T phase. The moving contacts of the device are manually closed to the fixed contacts at 0 ms and instantaneously begin to separate automatically due to the repulsion force caused by short-circuit current. It is observed that the arc voltage rises as the contact gap increases and, after passing the current zero point (A), the arc polarity reverses to



(b) Voltage waveforms.

Fig. 4. Current and voltage waveforms of a three-phase MCCB switching test under 483 V and 20 kA condition: A is the first current zero point in R phase and B is the first current zero point in T phase.

match the current polarity in the R phase. After instantaneous re-ignition, the re-ignition arc voltage is recorded as a relatively high value when compared with the exit arc voltage, and finally the arc current is interrupted at the first current zero point (B) of the T phase. The exit and re-ignition arc voltage are directly measured from the arc voltage waveforms. The system voltages at the current zero points (A and B) are obtained through the extrapolation using the time period from the current zero point to the last zero moment of the system voltage prior to the arc ignition (Δt_1 and Δt_2).

In the case of the open interruption, the system voltage at the current zero point is computed by the extrapolation method based on the first zero point of the system voltage after the arc extinction.

If instantaneous re-ignition occurs, the data of the next current zero event are measured, which is either a successful interruption or delayed re-ignition.

3) Voltage ratio

Figure 5 shows the equivalent circuit diagram of the three-phase switching test and the circuit equation of the

R-phase based on Kirchhoff's voltage law can be expressed as [14],

$$U_{sys_{R}}(t) = I_{R}(t)R_{R} + L_{R}\frac{dI_{R}(t)}{dt} + U_{arc_{R}}(t) + U_{N}.$$
 (1)

We can get (2), (3) and (4) since the three-phase power sources are synchronized.

$$U_{sys_{R}}(t) + U_{sys_{S}}(t) + U_{sys_{T}}(t) = 0.$$
 (2)

$$I_R(t) + I_S(t) + I_T(t) = 0.$$
 (3)

$$\frac{dI_R(t)}{dt} + \frac{dI_S(t)}{dt} + \frac{dI_T(t)}{dt} = 0.$$
(4)

The voltage at the neutral point in the power source part can be calculated from (5) by using the three circuit equations of each phase and (2) - (4).

$$U_{N} = -\frac{U_{arc_{R}}(t) + U_{arc_{S}}(t) + U_{arc_{T}}(t)}{3}.$$
 (5)

It is assumed that the recovery voltage applied across each phase of the LVSD is composed of the system voltage and the neutral point voltage. Since the arc voltage becomes zero at the current zero point, the recovery voltage across the R phase can be written as

$$U_{rec_{R}} = U_{sys_{R}}(t) + \frac{U_{arc_{S}}(t) + U_{arc_{T}}(t)}{3}.$$
 (6)

The voltage ratio is defined as the ratio of the recovery voltage to the exit arc voltage. For the three-phase and single-phase system, the voltage ratio can be formulated as (7) and (8), respectively,

$$Voltage \ ratio = \frac{U_{rec_j}}{U_{exit_j}},\tag{7}$$

$$Voltage \ ratio = \frac{U_{sys}}{U_{exit}}, \qquad (8)$$

where U_{exit} is the exit arc voltage and *j* is the index of the phase. In the single-phase test, only the system voltage is assumed as the recovery voltage.

4) Polarity between the recovery voltage and exit arc voltage When comparing the polarity of the recovery and exit arc voltage, there are two possible cases: the same polarity or opposing polarities. If there is a strong current limiting effect and a high exit arc voltage during the interruption process, the current drops to zero prior to the zero point of the system voltage and the same polarity case is observed.



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Fig. 5. Equivalent circuit diagram of a three-phase switching test: U_{sys} is the system voltage, I is short-circuit current, U_{arc} is the arc voltage, U_N is the voltage at the neutral point, R is the resistance, L is the inductance and the subscripts (R, S and T) represent each phase of the circuit.

III. RESULTS AND DISCUSSION

The exit arc voltage, proposed by Hauer [8], [9], is the simplest evaluator to predict instantaneous re-ignition, which is easy to implement in an industrial design scenario; however, this evaluator does not consider the recovery voltage, which is the source of the breakdown (re-ignition) and its limitation in predicting successful interruption is observed in the switching test data (Fig. 6). Firstly, there are some successful interruption cases where the exit arc voltage is too small to forecast the success and therefore a failed interruption is expected according to the exit arc voltage. Secondly, there is no clear threshold to distinguish a successful and failed interruption in the evaluator of the exit arc voltage as a sole evaluator and to predict re-ignition more accurately, the voltage ratio is introduced in this study, as in (7) and (8).

A. Exit arc voltage as an Evaluator

Figure 6 presents the full data of the correlation between arc re-ignition occurrence and the absolute value of the exit arc voltage in 10 kA, 20kA, 55 kA and 100 kA switching tests. Since each point corresponds to a different test condition or device design, a large variation in the exit arc voltage is observed as expected. If the exit arc voltage exceeds 400V it is plotted as 400 V. There are 30 successful interruptions with the same polarities between the recovery and exit arc voltage, 74 successful ones with the opposing polarities, 31 instantaneous re-ignition events and 6 delayed re-ignition events in the switching data. In general, the absolute value of the exit arc voltage is low in the case of instantaneous re-ignition whereas a high value is observed in the successful interruption cases. But there are two limitations in the usage of the exit arc voltage as an evaluator for instantaneous re-ignition as presented in Fig. 6. The average value of the exit arc voltage of all instantaneous re-ignition events is 47 V, however two successful cases (A and B) are marked below this average, which is not explained by the evaluator of the exit arc voltage alone. Additionally, there is no clear threshold between successful and failed interruptions. Except A and B points, the minimum exit arc voltage in the



Fig. 6. Re-ignition occurrences depending on the exit arc voltage: the exit arc voltage is plotted as 400 V if it is greater than 400 V.

case of the successful interruption is 73 V, whereas the maximum value in the instantaneous re-ignition case is 149 V. There are 20 successful cases and 6 instantaneous re-ignitions in this overlapping region between 73 V and 149 V, which are not predicted by the exit arc voltage, accurately.

The delayed re-ignition phenomena cannot be predicted by the exit arc voltage. This may be attributed to a fault in the LVSD operating mechanism detected during the post-test examination of the device. As an example of the post-test examination, if the movable contact is not locked by the operating mechanism after opening, it can rebound and the contact gap will reduce, causing a failure.

B. Voltage Ratio as an Evaluator

Figure 7 uses the same test data as Fig. 6, but now shows the dependence of the re-ignition occurrence on the voltage ratio defined in (7) and (8). Values below a voltage ratio of -3.0 are plotted as -3.0. Three groups of the voltage ratio are observed: the first (region 1) is the positive ratio (in the case of the same polarity between the exit and system voltage), the second (region 2) is the range of 0 to -2.0 and the third (region 3) is less than -2.0. Omitting the cases of delayed re-ignition, all switching trials are successful in the range of the positive voltage ratio. There are 74 successful interruptions with the opposing polarity and 2 instantaneous re-ignition cases in the second region of 0 to -2.0 voltage ratio. Only instantaneous re-ignition events are seen in the range below -2.0. Particularly, both A and B successful interruptions are predicted by the voltage ratio, which is -0.52 and -1.37, respectively, but not by the exit arc voltage evaluator. Overall, it can be concluded that the voltage ratio is a more detailed and accurate evaluator to forecast the switching performance than the exit arc voltage.

Like the exit arc voltage, the voltage ratio evaluator cannot predict delayed re-ignition that is associated with the failure of the operating mechanism of the LVSD.



Fig. 7. Re-ignition occurrences depending on the voltage ratio; the voltage ratio is plotted as -3.0 if it is lower than -3.0.

C. Discussion

1) The region of the positive voltage ratio

The successful operation with a positive voltage ratio can be explained by the inconsistency of the circuit equation near the current zero point. As the voltage drop across the external resistive load is negligible, the circuit equation near the current zero point in the single-phase test can be expressed as

$$U_{sys}(t) - U_{arc}(t) = L \frac{dI(t)}{dt}.$$
(9)

For the three-phase circuit, the voltage between the system voltage and the voltage at the neutral point is required in (9). If instantaneous re-ignition occurs in the range of the positive voltage ratio with the decreasing current where both system voltage and exit arc voltage are initially positive, the value of the left hand side in (9) prior to the current zero moment is negative due to a higher arc voltage compared to the system voltage; but it switches to positive immediately after the current zero moment due to a positive system voltage and the inversion of the arc voltage to negative. However, the value of the right hand side is still negative because the current continues to decrease after the current zero point. It indicates that such situations are not possible and the only solution is an open circuit, i.e. successful interruption.

2) The region of the negative voltage ratio

The situation of the negative voltage ratio can be explained with the aid of the race theory presented by Slepian [1]. Instantaneous re-ignition occurs in the case of the recovery voltage (which is effectively an open circuit voltage across the gap in the device) being higher than the breakdown voltage immediately after the current zero point. As the value of the arc voltage is determined by the power input required to sustain the arc [2], the breakdown voltage should be greater than the arc voltage.



Fig. 8. Relationship between the absolute values of the re-ignition arc voltage and exit arc voltage; the absolute value of the re-ignition arc voltage is higher than that of the exit arc voltage in all cases.

It is observed from Fig. 8 that the absolute value of the re-ignition arc voltage (the arc voltage immediately after the current zero point) is greater than that of the exit arc voltage in all instantaneous re-ignition cases. From this test result, it is apparent that the exit arc voltage has a significant influence on the arc characteristics immediately after the current zero point. Further, Fig. 8 shows that a different test condition leads to very different re-ignition arc voltage which in turn indicates that the exit arc voltage itself is probably not the best evaluator.

It is in agreement with the theory, that there is no instantaneous re-ignition in the range of 0 to -1.0 voltage ratio, i.e. when the breakdown voltage is higher than the recovery voltage (note that the breakdown voltage is always higher than the exit arc voltage due to cooling effects). In practice, the threshold between successful and unsuccessful interruptions is observed at more relaxed conditions, when the voltage ratio of approximately -2.0 (see Fig. 7). There are two possible explanations for the observed threshold. The increase in the breakdown voltage due to plasma cooling and reduction in plasma conductivity is possible; therefore, a higher than the exit arc voltage is needed to support a colder arc. The other explanation can be a switching of cathodic and anodic sheaths over the splitter plate surfaces. This switch takes place just before re-ignition when the sufficient recovery voltage is applied to 1) compensate the voltage drop (which corresponds to the exit arc voltage) in the existing sheaths allowing electrons and ions to move in the opposite direction; 2) to create an additional voltage drop with opposite polarities accelerating electrons and ions for the ions generation at the anodic sheath and the electron emission from the cathode by ions bombardment. The magnitude of this additional voltage is equal to the exit arc voltage if we assume that the latter one is almost all due to the surface sheaths.

There are rare cases when re-ignition occurs at the ratio above -2.0. We believe that these cases correspond to situations when the arc is attached at the edges of some splitter plates prior to the current zero point and the arc re-ignites directly through an air gap skipping the edges. This re-ignition does not require the sheath switch as the arc is established through the hot gas region in front of the splitter plates without creating an additional voltage drop in the cathode and anode sheath. In this case, the breakdown voltage can be less than 200% of the exit arc voltage, however, always greater than 100% of the exit arc voltage. The modelling can select the LVSD design to push the arc further towards splitter plates and this would allow to consider the relaxed re-ignition criterion, the voltage ratio > -2.0.

IV. CONCLUSION

In this paper, an experimental investigation has been carried out regarding re-ignition evaluators that can predict the switching performance of LVSDs prior to empirical laboratory testing of real products. The following conclusions can be drawn.

- 1) The voltage ratio (which is defined as the ratio of the recovery voltage to the exit arc voltage) is a reliable evaluator and provides more information than the exit arc voltage.
- 2) Instantaneous re-ignition does not occur when the voltage ratio is positive or it lies in the range of 0 to -1.0. It can be used as a 'strict' global evaluator to predict the switching performance of the LVSD. Also, there is an experimentally observed 'soft' threshold of the voltage ratio at approximately -2.0, which distinguishes most of the successful interruptions from instantaneous re-ignitions. The rare cases of re- ignition when the ratio lies in the range of -1.0 to -2.0 are attributed to the arc attachment at the edges of splitter plates and re-ignition directly through an air gap without the sheath voltage.
- 3) Delayed re-ignition cannot be predicted by using either the exit arc voltage or voltage ratio; however, it was diagnosed with the result of failure in the LVSD operating mechanism. It should be the subject of mechanical design improvement, rather than optimization of electrical arc dynamics.

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